Name: China Resources Microelectronics (Chongqing) Co., Ltd. Laboratory

Address: 1/F., Building A, No.25, Xiyong Avenue, Shapingba District, Chongqing, China

Registration No. CNAS L20336

Accreditation Criteria: ISO/IEC 17025:2017 and relevant requirements of CNAS

Effective Date: 2025-05-26 Expiry Date: 2030-03-06

SCHEDULE 3 ACCREDITED TESTING SCOPE

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
1	Electronic components	1	HTRB	Temperature, Bias, and Operating Life JESD22-A108G:2022 4.2.3.3	Accredited only for:Temperature:(50°C ~175°C）, Voltage:(5 V~2000V). Rental Equipment is included.	2025-05-26
				TEST METHODS FOR SEMICONDUCTOR DEVICES MIL-STD-750-1B 18 April 2023 1038.5 condition A	Accredited only for：diodes，Temperature:(50°C~175°C）,Voltage:(5V~20	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					00V). Rental Equipment is included.	
				TEST METHODS FOR SEMICONDUCTOR DEVICES MIL-STD-750-1B 18 April 2023 1039.4 condition A	Accredited only for transistors，Temperature:(50℃~175℃）,Voltage:(5V~2000V). Rental Equipment is included.	2025-05-26
		2	HTGB	Temperature, Bias, and Operating Life JESD22-A108G:2022 4.2.3.4	Accredited only for:Temperature:(50℃~175℃）,Voltage:(5V~2000V). Rental Equipment is included.	2025-05-26
		3	LTS	Low Temperature Storage Life JESD22-A119A:2015	Rental equipment is included.	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
		4	HTS	High Temperature Storage Life JESD22-A103E.01:2021	Accredited only for:Temperature:（50℃~175℃），only include conditionA、conditionB、conditionC. Rental equipment is included.	2025-05-26
		5	HAST	Highly Accelerated Temperature and Humidity Stress Test JESD22-A110E.01:2021	Accredited only for:Temperature:130℃,Humidity:85%RH,Pressure:230kPa,Voltage:(5V~1200V). Rental equipment is included.	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
		6	H3TRB	Steady-State Temperature-Humidity Bias Life Test JESD22-A101D.01:2021	Accredited only for:Temperature:85℃, Humidity:85%RH,Voltage:(5V~1200V). Rental equipment is included.	2025-05-26
		7	UHAST	Accelerated Moisture Resistance - Unbiased HAST JESD22-A118B.01:2021	Accredited only for:Temperature:（121℃~130℃）,Humidity:(85%RH~100%RH）,Pressure:（121kPa~230kPa). Rental equipment is included.	2025-05-26
		8	AC	Accelerated Moisture Resistance -Unbiased Autoclave JESD22-A102E:2015	Accredited only for:Temperature:	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					（121℃~130℃）,Humidity:(85%RH~100%RH）,Pressure:（121kPa~230kPa). Rental equipment is included.	
		9	Pre-conditioning	Preconditioning of NonhermeticSurface Mount Devices Prior toReliability Testing JESD22-A113I:2020	Rental equipment is included.	2025-05-26
2	Electronic components	1	HTRB	FAILURE MECHANISM BASEDSTRESS TEST QUALIFICATIONFORDISCRETE SEMICONDUCTORSIN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1, 2021 Tab2 B1	Accredited only for diodes and transistors, Temperature:(50℃~175℃）,Voltage:(5V~2000V). Rental equipment is included.	2025-05-26
		2	HTGB	FAILURE MECHANISM BASEDSTRESS TEST QUALIFICATIONFORDISCRETE SEMICONDUCTORSIN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,	Accredited only for:Temper	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
				2021 Tab2 B2	ature:(50℃~175℃）, Voltage:(5V~2000V). Rental equipment is included.	
		3	HAST	FAILURE MECHANISM BASEDSTRESS TEST QUALIFICATIONFORDISCRETE SEMICONDUCTORSIN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1, 2021 Tab2 A2	Accredited only for:Temperature:130℃,Humidity:85%RH,Pressure:230kPa,Voltage:(5V~1200V). Rental equipment is included.	2025-05-26
		4	H3TRB	FAILURE MECHANISM BASEDSTRESS TEST QUALIFICATIONFORDISCRETE SEMICONDUCTORSIN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1, 2021 Tab2 A2 alt	Accredited only for:Temperature:85℃, Humidity:85%RH,Voltage:(5V~1200V). Rental equipment	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					is included.	
		5	UHAST	FAILURE MECHANISM BASEDSTRESS TEST QUALIFICATIONFORDISCRETE SEMICONDUCTORSIN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1, 2021 Tab2 A3	Accredited only for:Temperature:（121℃~130℃）,Humidity:(85%RH~100%RH）,Pressure:（121kPa~230kPa). Rental equipment is included.	2025-05-26
		6	AC	FAILURE MECHANISM BASEDSTRESS TEST QUALIFICATIONFORDISCRETE SEMICONDUCTORSIN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1, 2021 Tab2 A3 alt	Accredited only for:Temperature:（121℃~130℃）,Humidity:(85%RH~100%RH）,Pressure:（121kPa~230kPa). Rental	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					equipment is included.	
		7	Pre-conditioning	Moisture/Reflow SensitivityClassification forNon-hermetic Surface MountDevices (SMDs) J-STD-020F December,2022	Rental equipment is included.	2025-05-26
				FAILURE MECHANISM BASEDSTRESS TEST QUALIFICATIONFORDISCRETE SEMICONDUCTORSIN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1, 2021 Tab2 A1	Rental equipment is included.	2025-05-26
		8	IOL	ENVIRONMENTAL TEST METHODS FOR SEMICONDUCTOR DEVICESPART 1: TEST METHODS 1000 THROUGH 1999 MIL-STD-750-1B 18 April 2023 Method 1037.3	Rental equipment is included.	2025-05-26
				FAILURE MECHANISM BASEDSTRESS TEST QUALIFICATIONFORDISCRETE SEMICONDUCTORSIN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1, 2021 Tab2 A5	Rental equipment is included.	2025-05-26
		9	HTS	Semiconductor devices – Mechanical and climatic test methods – Part 6: Storage at high temperature IEC 60749-6 Mar,2017	Accredited only for:Temperature:（50℃~175℃）. Rental equipment is included.	2025-05-26
		10	TC	Temperature Cycling JESD22-A104F.01 April,2023	Accredited only for:Temperature:（-	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
					65℃~150℃）. Rental equipment is included.	
				FAILURE MECHANISM BASEDSTRESS TEST QUALIFICATIONFORDISCRETE SEMICONDUCTORSIN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1, 2021 Tab2 A4	Only measure:Temperature:（-65℃~150℃）. Rental equipment is included.	2025-05-26
		11	AM	Acoustic Microscopy forNon-Hermetic EncapsulatedElectronic Devices J-STD-035A December,2022	Rental equipment.	2025-05-26
		12	TH	Steady-State Temperature-Humidity Bias Life Test JESD22-A101D.01 January,2021	Accredited only for:Temperature:60℃~85℃,Humidity:60%RH~85%RH. Rental equipment is included.	2025-05-26
		13	WBP	MECHANICAL TEST METHODS FOR SEMICONDUCTOR DEVICESPART 2: TEST METHODS 2001 THROUGH 2999 MIL−STD−750−2B 22 June 2022 2037.1	Accredited only for: WBP≤5kg	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
		14	WBS	WIRE BOND SHEAR TEST AEC - Q101-003 - REV-A July 18,2005	Accredited only for：WBS≤100kg	2025-05-26
		15	ESD HBM	HUMAN BODY MODEL (HBM)ELECTROSTATIC DISCHARGE (ESD)TEST AEC-Q101-001 REV-A July18,2005	Accredited only for :0V~8000V. Rental equipment.	2025-05-26
				ENVIRONMENTAL TEST METHODS FOR SEMICONDUCTOR DEVICESPART 1: TEST METHODS 1000 THROUGH 1999 MIL-STD-750-1B 18 April 2023 1020.7	Accredited only for:0V~8000V. Rental Equipment.	2025-05-26
		16	Electrical Test	Semiconductor devices –Part 2: Discrete devices – Rectifier diodes IEC 60747-2 Apr,2016 6.1.2.3/6.1.3/6.1.4	Accredited only for:diodes. Rental equipment is included.	2025-05-26
				Semiconductor devices - Discrete devices - Part 8: Field-effect transistors IEC 60747-8 Dec,2010+AMD1 Jun,2021 CSV 6.3.1/6.3.2/6.3.3/6.3.4/6.3.5/6.3.15	Accredited only for:transistors. Rental equipment is included.	2025-05-26

№	Test Object	Item/Parameter		Standard or Method	Note	Effective Date
		№	Item/ Parameter			
				Semiconductor devices –Part 9: Discrete devices – Insulated-gate bipolar transistors (IGBTs) IEC 60747-9 Nov，2019 6.3.1/6.3.2/6.3.3/6.3.4/6.3.5/Annex A	Accredited only for:IGBTs. Rental equipment is included.	2025-05-26

在线扫码获取验证